	Application No.	Applicant(s)
Notice of Allowability	10/697,647	HAMASHIMA ET AL.
	Examiner	Art Unit
	Thuy V. Tran	2821
The MAILING DATE of this communication appeal all claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT R	(OR REMAINS) CLOSED in this applied or other appropriate communication IGHTS. This application is subject to	plication. If not included will be mailed in due course. THIS
1. \boxtimes This communication is responsive to <u>amendment submitte</u>	d 10/30/2006.	
2. ☑ The allowed claim(s) is/are <u>1-4 and 6-10</u> .		
 Acknowledgment is made of a claim for foreign priority ur a)	e been received. e been received in Application No cuments have been received in this	national stage application from the
noted below. Failure to timely comply will result in ABANDONN THIS THREE-MONTH PERIOD IS NOT EXTENDABLE. 4. A SUBSTITUTE OATH OR DECLARATION must be subm	MENT of this application.	
INFORMAL PATENT APPLICATION (PTO-152) which give		
5. CORRECTED DRAWINGS (as "replacement sheets") mus	st be submitted.	
(a) including changes required by the Notice of Draftspers	son's Patent Drawing Review (PTO-	948) attached
1) 🔲 hereto or 2) 🔲 to Paper No./Mail Date		·
(b) including changes required by the attached Examiner's Paper No./Mail Date		
Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in t		
 DEPOSIT OF and/or INFORMATION about the depo attached Examiner's comment regarding REQUIREMENT 		
Attachment(s) 1. Notice of References Cited (PTO-892) 2. Notice of Draftperson's Patent Drawing Review (PTO-948) 3. Information Disclosure Statements (PTO/SB/08), Paper No./Mail Date 4. Examiner's Comment Regarding Requirement for Deposit	5. ☐ Notice of Informal P 6. ☐ Interview Summary Paper No./Mail Dat 7. ☐ Examiner's Amendr	(PTO-413), te
of Biological Material	9. Other	while
		HUYV.TRAN IARY EXAMINER

DETAILED ACTION

This Office Action is responsive to the Applicants' amendment submitted on October 20, 2006. In virtue of this amendment, claims 5 and 11-12 are canceled, and thus, claims 1-4 and 6-10 are now presented in the instant application.

Allowable Subject Matter

1. Claims 1-4 and 6-10 are allowed.

Reasons for Allowance

2. The following is an examiner's statement of reasons for allowance:

Prior art fails to disclose or fairly suggest:

- An electron beam apparatus comprising a deflector for deflecting said secondary electron beams in said secondary optical system wherein said deflector is controlled to deflect said plurality of secondary electron beams to prevent said plurality of secondary electron beams from moving on said detector in response to the scanning of said plurality of primary electron beams, in combination with the remaining claimed limitations as called for in independent claim 1 (claims 2 and 4 are allowed since they are dependent on claim 1);
- An electron beam apparatus further comprising a number of memories twice as much
 as a number of the detectors for storing digital signals generated by A/D converting
 the detection signals, and change-over switches disposed in front of and at a back of
 the memories, in combination with the remaining claimed limitations as called for in
 independent claim 3;

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- An electron beams apparatus wherein said electron gun comprises a multi-emitter machined as a cathode including a plurality emitters integrated thereon, a heater for heating said multi-emitter, and a supporter for fixing said multi-emitter and said heater at given positions, in combination with the remaining claimed limitations as called for in independent claim 6 (claims 7-9 are allowed since they are dependent on claim 6); and
- An electron beam apparatus comprising a condenser lens for converging the plurality of primary electron beams emitted from said electron gun, a multi-aperture plate having a plurality of apertures, a demagnification lens for demagnifying the plurality of primary electron beams, wherein said condenser lens forms a crossover image at a point between said multi-aperture plate and said demagnification lens, in combination with the remaining claimed limitations as called for in independent claim 10.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Inquiry

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Thuy V. Tran whose telephone number is (571) 272-1828. The examiner can normally be reached on M-F (8:00 AM -4:00 PM).

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Timothy P. Callahan can be reached on (571) 272-1740. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

11/22/2006

THUY V.TRAN
PRIMARY EXAMINER